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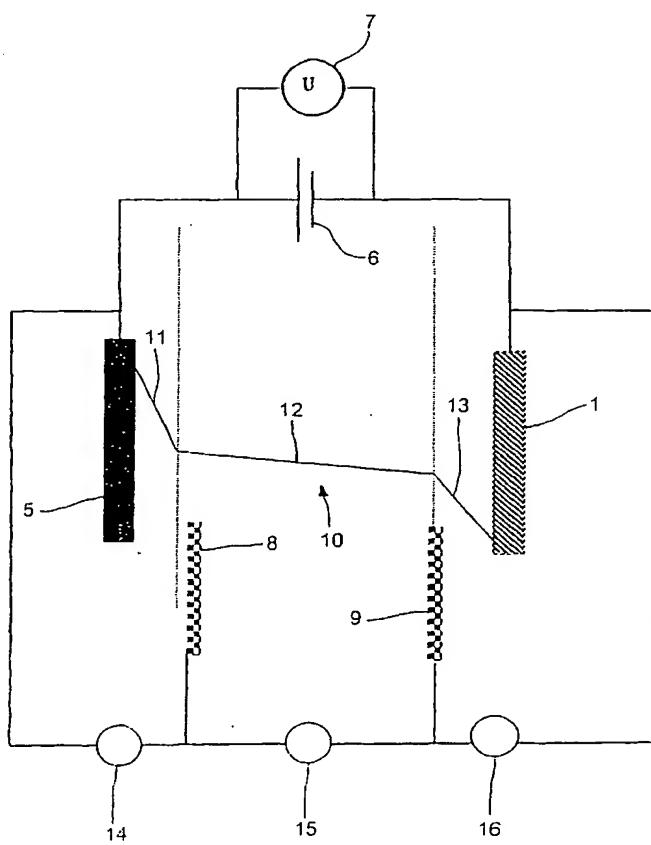
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[Continued on next page]

(54) Title: DEVICE AND METHOD FOR MONITORING AN ELECTROLYTIC PROCESS



(57) Abstract: In manufacturing integrated circuits voids in the metal layer may readily form during electrolytic metal deposition. In order to avoid these faults which adversely affect the functionality of the circuits, the invention suggests to utilize for metal deposition an electrolysis device comprised of at least one anode and at least one cathode and in which at least one reference electrode is disposed at the surface of the at least one anode or at the surface of the at least one cathode. A voltmeter is respectively provided for detecting the electric voltages between the at least one anode and the at least one reference electrode and between the at least one reference electrode and the at least one cathode.



SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

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B. FIELDS SEARCHED

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Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

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C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 6 261 433 B1 (LANDAU UZIEL) 17 July 2001 (2001-07-17) column 14, lines 7-9	1
X	GB 871 203 A (ARTUR RIEDEL; FRANZ BACHMANN) 21 June 1961 (1961-06-21) claims 1-7	1,3,4,7, 9,10
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Further documents are listed in the continuation of box C.

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